Attorney Docket No. 04216/LH

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Yoshinori IKETAKI

Serial No. : 10/821,474

Filed : April 8, 2004

For : MICROSCOPE AND ITS OPTICAL CONTROLLING METHOD

Art Unit :

CUSTOMER NO.: 01933

PRELIMINARY AMENDMENT

Commissioner for Patents
P.O. BOX 1450
Alexandra, VA 22313-1450

Att: MS - MISSING PARTS

S I R :

CERTIFICATE OF MAILING

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Sharon Portnoy

Dated: August 12, 2004

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Amendments to the Specification are described on page 2 of this paper.

Remarks begin on page 3 of this paper.

Please delete the abstract and add the following new abstract:

Abstract

A microscope includes a first deflection device which deflects first light from a first light source that excites a molecule included in a specimen from the ground-state to a first electronically excited state, and a two dimensionally second deflecting device which deflects second light from a second light source to excite the molecule from the first exciting state to a second exciting state with a higher energy level. A combining device synthesizes the deflected first light and second light on the same optical axis or on a mutually parallel optical axis. A third deflection device deflects the synthesized first light and the second light simultaneously. Luminescence is detected by adjusting the optical axes of the first light to the third light by the first to third deflection device, and by overlapping part of these lights by a beam-condensing optical system and irradiating them on the specimen.